

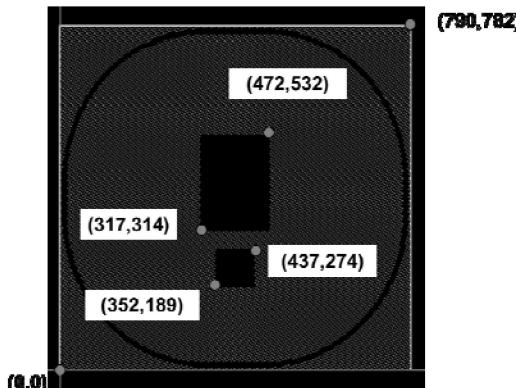
HSM200R600

600V N Channel MOSFETs Wafer Datasheet



Die Description

Parameter	Parameter	Rating	CHIP DRAWING
Die Size (with SL)	850 X 842		
Gate Pad Size	85 X 85	um ²	
Source Pad Size	155 X 218		
Scribe Line Size	60	um	
Wafer size	200	mm	
Wafer Thickness	10	mil	
Metallization	4um , Al-Cu (0.5%)		
Back Metallization	Ti/Ni/Ag , 1/3/10KA		
Gate Bond Wire	0.8 mil Au/Cu x 1		
Source Bond Wire	0.8 mil Au/Cu x 1		
Estimated Gross Die	40,000		



Absolute Maximum Ratings T_c=25°C unless otherwise noted

Symbol	Parameter	Rating	Unit
V _{DSS}	Drain-Source Voltage	600V	V
V _{GSS}	Gate-Source Voltage	±30V	V
T _J	Operating Junction Temperature Range	-50 to 150°C	°C
T _{STG}	Storage Temperature Range	-50 to 150°C	°C

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	600	---	---	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =600V , V _{GS} =0V , T _J =25°C	---	---	1	uA
		V _{DS} =480V , V _{GS} =0V , T _J =85°C	---	---	10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±30V , V _{DS} =0V	---	---	±100	nA
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V , I _D =0.2A	---	120	200	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.5	2.4	3.5	V

Note : 1. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.

2. RDSON calculated by SOT23 Package Type